DISCRETE SEMICONDUCTORS

DATA SHEET

BF1202; BF1202R; BF1202WR N-channel dual-gate PoLo MOS-FETs

Product specification Supersedes data of 2000 Mar 29 2010 Sep 16



N-channel dual-gate PoLo MOS-FETs BF1202; BF1202R; BF1202WR

FEATURES

- Short channel transistor with high forward transfer admittance to input capacitance ratio
- · Low noise gain controlled amplifier
- Partly internal self-biasing circuit to ensure good cross-modulation performance during AGC and good DC stabilization.

APPLICATIONS

 VHF and UHF applications with 3 to 9 V supply voltage, such as digital and analogue television tuners and professional communications equipment.

DESCRIPTION

Enhancement type N-channel field-effect transistor with source and substrate interconnected. Integrated diodes between gates and source protect against excessive input voltage surges. The BF1202, BF1202R and BF1202WR are encapsulated in the SOT143B, SOT143R and SOT343R plastic packages respectively.

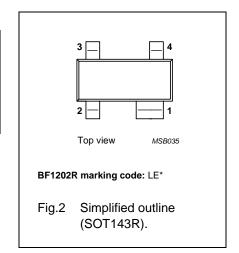
PINNING

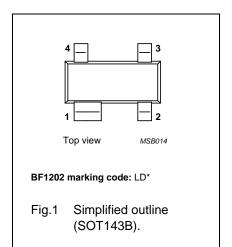
PIN	DESCRIPTION
1	source
2	drain
3	gate 2
4	gate 1

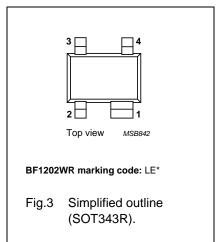
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* = t : made in Malaysia







QUICK REFERENCE DATA

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
V _{DS}	drain-source voltage		_	_	10	V
I _D	drain current		_	_	30	mA
P _{tot}	total power dissipation		_	_	200	mW
y _{fs}	forward transfer admittance		25	30	40	mS
C _{ig1-ss}	input capacitance at gate 1		_	1.7	2.2	pF
C _{rss}	reverse transfer capacitance	f = 1 MHz	_	15	30	fF
F	noise figure	f = 800 MHz	_	1.1	1.8	dB
X _{mod}	cross-modulation	input level for k = 1% at 40 dB AGC	100	105	_	dBμV
T _j	operating junction temperature		_	_	150	°C

CAUTION

This product is supplied in anti-static packing to prevent damage caused by electrostatic discharge during transport and handling.

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LIMITING VALUES

In accordance with the Absolute Maximum Rating System (IEC 60134).

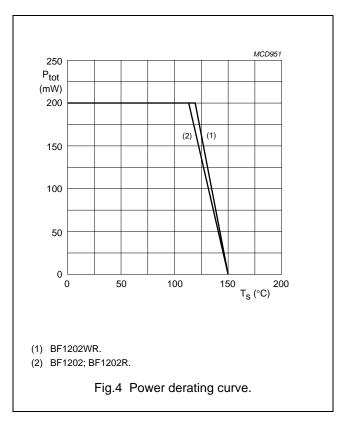
SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
V _{DS}	drain-source voltage		_	10	V
I_D	drain current		_	30	mA
I _{G1}	gate 1 current		_	±10	mA
I_{G2}	gate 2 current		_	±10	mA
P _{tot}	total power dissipation				
	BF1202; BF1202R	T _s ≤ 113 °C; note 1	_	200	mW
	BF1202WR	$T_s \le 119 ^{\circ}C$; note 1	_	200	mW
T _{stg}	storage temperature		-65	+150	°C
Tj	operating junction temperature		_	150	°C

Note

1. T_s is the temperature of the soldering point of the source lead.

THERMAL CHARACTERISTICS

SYMBOL	PARAMETER	VALUE	UNIT
R _{th j-s}	thermal resistance from junction to soldering point		
	BF1202; BF1202R	185	K/W
	BF1202WR	155	K/W



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STATIC CHARACTERISTICS

 $T_j = 25$ °C unless otherwise specified.

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
V _{(BR)DSS}	drain-source breakdown voltage	$V_{G1-S} = V_{G2-S} = 0; I_D = 10 \mu A$	10	_	V
V _{(BR)G1-SS}	gate 1-source breakdown voltage	V _{G2-S} = V _{DS} = 0; I _{G1-S} = 10 mA	6	_	V
V _{(BR)G2-SS}	gate 2-source breakdown voltage	$V_{G1-S} = V_{DS} = 0$; $I_{G2-S} = 10 \text{ mA}$	6	_	V
V _{(F)S-G1}	forward source-gate 1 voltage	$V_{G2-S} = V_{DS} = 0$; $I_{S-G1} = 10 \text{ mA}$	0.5	1.5	V
V _{(F)S-G2}	forward source-gate 2 voltage	$V_{G1-S} = V_{DS} = 0$; $I_{S-G2} = 10 \text{ mA}$	0.5	1.5	V
V _{G1-S(th)}	gate 1-source threshold voltage	$V_{G2-S} = 4 \text{ V}; V_{DS} = 5 \text{ V}; I_D = 100 \mu\text{A}$	0.3	1.0	V
V _{G2-S(th)}	gate 2-source threshold voltage	$V_{G1-S} = 5 \text{ V}; V_{DS} = 5 \text{ V}; I_D = 100 \mu\text{A}$	0.3	1.2	V
I _{DSX}	drain-source current	$V_{G2-S} = 4 \text{ V}; V_{DS} = 5 \text{ V}; R_{G1} = 120 \text{ k}\Omega;$ note 1	8	16	mA
I _{G1-SS}	gate 1 cut-off current	V _{G2-S} = V _{DS} = 0; V _{G1-S} = 5 V	_	50	nA
I _{G2-SS}	gate 2 cut-off current	V _{G1-S} = V _{DS} = 0; V _{G2-S} = 4 V	_	20	nA

Note

1. R_{G1} connects G_1 to $V_{GG} = 5$ V.

DYNAMIC CHARACTERISTICS

Common source; T_{amb} = 25 °C; V_{G2-S} = 4 V; V_{DS} = 5 V; I_D = 12 mA; unless otherwise specified.

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
y _{fs}	forward transfer admittance	pulsed; T _j = 25 °C	25	30	40	mS
C _{ig1-ss}	input capacitance at gate 1	f = 1 MHz	_	1.7	2.2	pF
C _{ig2-ss}	input capacitance at gate 2	f = 1 MHz	_	1	_	pF
C _{oss}	output capacitance	f = 1 MHz	_	0.85	_	pF
C _{rss}	reverse transfer capacitance	f = 1 MHz	_	15	30	fF
F	noise figure	$f = 10.7 \text{ MHz}; G_S = 20 \text{ mS}; B_S = 0$	_	9	11	dB
		$f = 400 \text{ MHz}; Y_S = Y_{S \text{ opt}}$	_	0.9	1.5	dB
		$f = 800 \text{ MHz}; Y_S = Y_{S \text{ opt}}$	_	1.1	1.8	dB
G _{tr}	power gain	$f = 200 \text{ MHz}; G_S = 2 \text{ mS}; B_S = B_{S \text{ opt}};$	_	34.5	_	dB
		$G_L = 0.5 \text{ mS}; B_L = B_{L \text{ opt}}$ $f = 400 \text{ MHz}; G_S = 2 \text{ mS}; B_S = B_{S \text{ opt}};$ $G_L = 1 \text{ mS}; B_L = B_{L \text{ opt}}$	_	30.5	_	dB
		$f = 800 \text{ MHz}; G_S = 3.3 \text{ mS}; B_S = B_{S \text{ opt}};$ $G_L = 1 \text{ mS}; B_L = B_{L \text{ opt}}$	_	26.5	_	dB
X _{mod}	cross-modulation	input level for $k = 1\%$; $f_w = 50$ MHz; $f_{unw} = 60$ MHz; note 1				
		at 0 dB AGC	90	_	_	dΒμV
		at 10 dB AGC	_	92	_	dBμV
		at 40 dB AGC	100	105	_	dΒμV

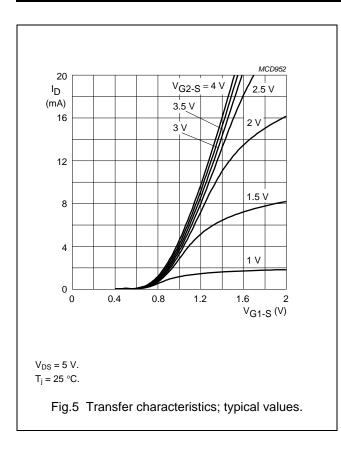
Note

1. Measured in Fig.21 test circuit.

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BF1202; BF1202R; BF1202WR



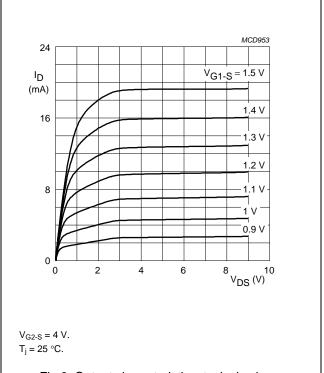
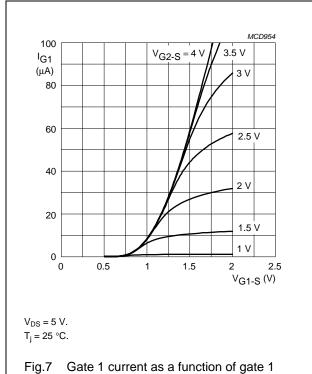
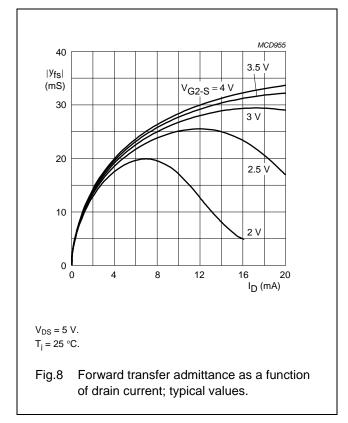


Fig.6 Output characteristics; typical values.



voltage; typical values.



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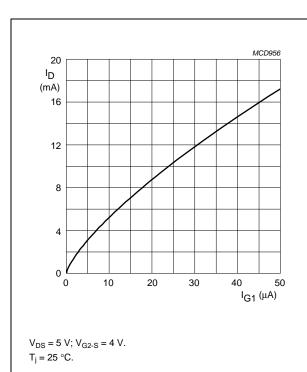


Fig.9 Drain current as a function of gate 1 current; typical values.

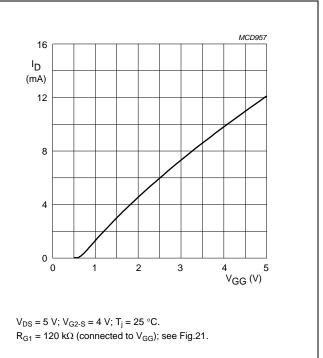


Fig.10 Drain current as a function of gate 1 supply voltage (= V_{GG}); typical values.

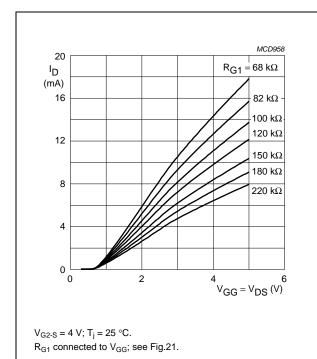
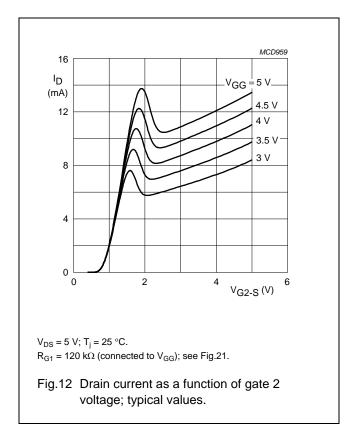
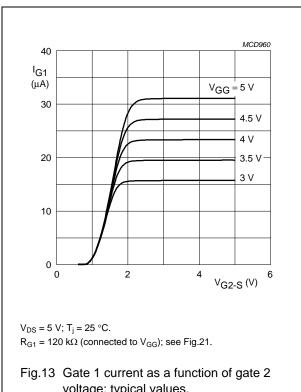


Fig.11 Drain current as a function of gate 1 (= V_{GG}) and drain supply voltage; typical values.

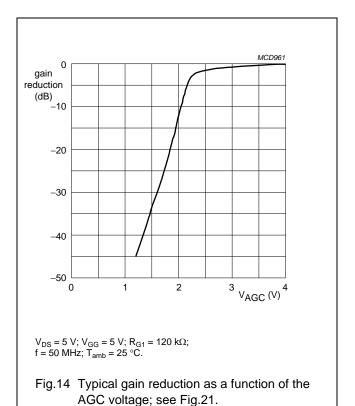


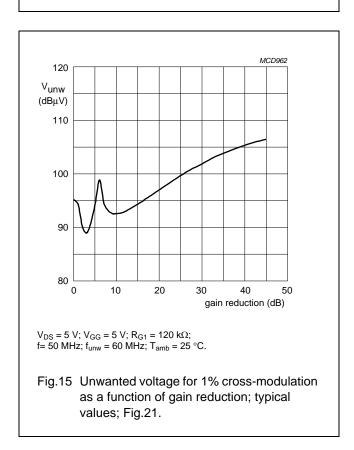
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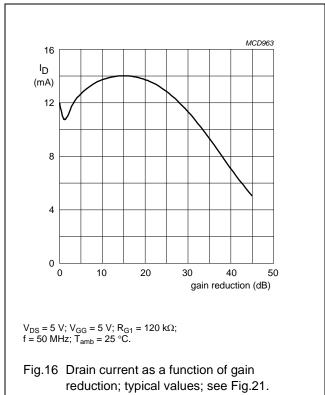
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voltage; typical values.







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BF1202; BF1202R; BF1202WR

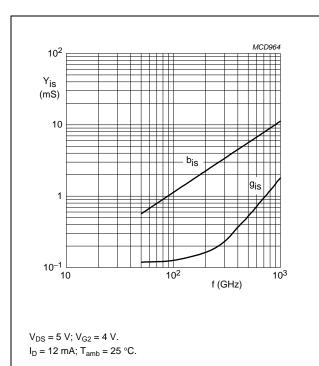


Fig.17 Input admittance as a function of frequency; typical values.

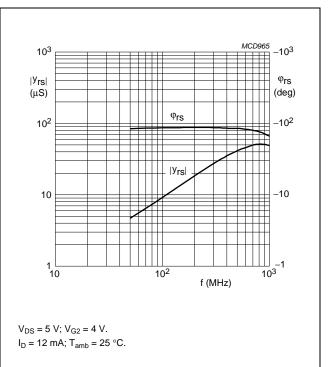


Fig.18 Reverse transfer admittance and phase as a function of frequency; typical values.

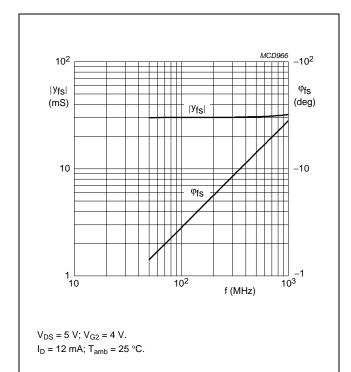
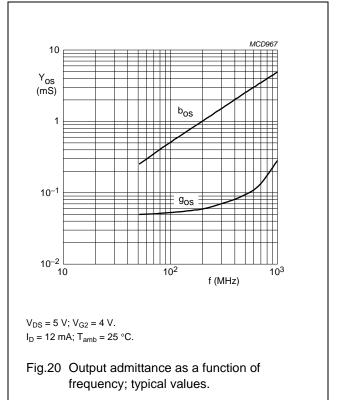


Fig.19 Forward transfer admittance and phase as a function of frequency; typical values.



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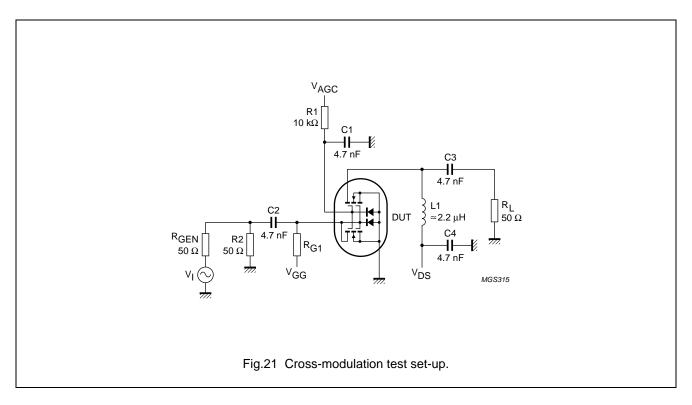


Table 1 Scattering parameters: $V_{DS} = 5 \text{ V}$; $V_{G2-S} = 4 \text{ V}$; $I_D = 12 \text{ mA}$; $T_{amb} = 25 ^{\circ}\text{C}$

	37 and 37 and 50 a 7 620 7 B 7 and 5 a							
f	s ₁₁		S ₁₁ S ₂₁		s ₁₂		s ₂₂	
(MHz)	MAGNITUDE (ratio)	ANGLE (deg)	MAGNITUDE (ratio)	ANGLE (deg)	MAGNITUDE (ratio)	ANGLE (deg)	MAGNITUDE (ratio)	ANGLE (deg)
50	0.988	-3.26	2.989	176.2	0.0005	92.6	0.995	-1.50
100	0.988	-6.52	3.017	172.5	0.0009	88.0	0.995	-3.01
200	0.984	-12.99	2.990	165.0	0.0018	82.5	0.994	-5.95
300	0.977	-19.39	2.949	157.6	0.0027	78.2	0.992	-8.86
400	0.965	-25.65	2.913	150.3	0.0036	75.4	0.990	-11.79
500	0.951	-31.76	2.853	143.2	0.0039	71.8	0.988	-14.65
600	0.936	-37.68	2.793	136.3	0.0042	69.9	0.986	-17.41
700	0.919	-43.42	2.727	129.5	0.0044	68.9	0.984	-20.10
800	0.903	-48.94	2.664	123.0	0.0043	68.5	0.980	-22.69
900	0.887	-54.25	2.593	116.7	0.0041	70.7	0.975	-25.27
1000	0.870	-59.34	2.518	110.5	0.0038	72.4	0.970	-27.90

Table 2 Noise data: $V_{DS} = 5 \text{ V}$; $V_{G2\text{-}S} = 4 \text{ V}$; $I_D = 12 \text{ mA}$; $T_{amb} = 25 ^{\circ}\text{C}$

f	F _{min}	$\Gamma_{\mathbf{c}}$	ppt	R _n
(MHz)	(dB)	(ratio)	(deg)	(Ω)
400	0.9	0.805	28.5	50
800	1.1	0.725	47.2	40

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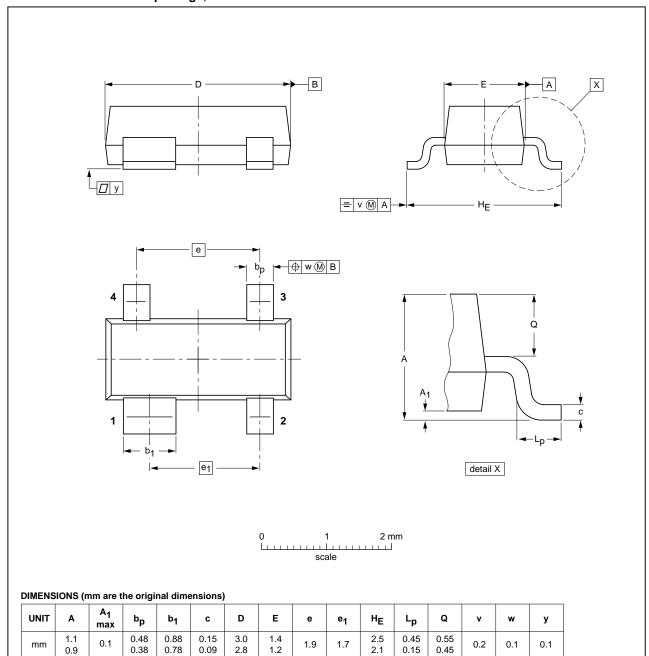
N-channel dual-gate PoLo MOS-FETs

BF1202; BF1202R; BF1202WR

PACKAGE OUTLINES

Plastic surface-mounted package; 4 leads

SOT143B



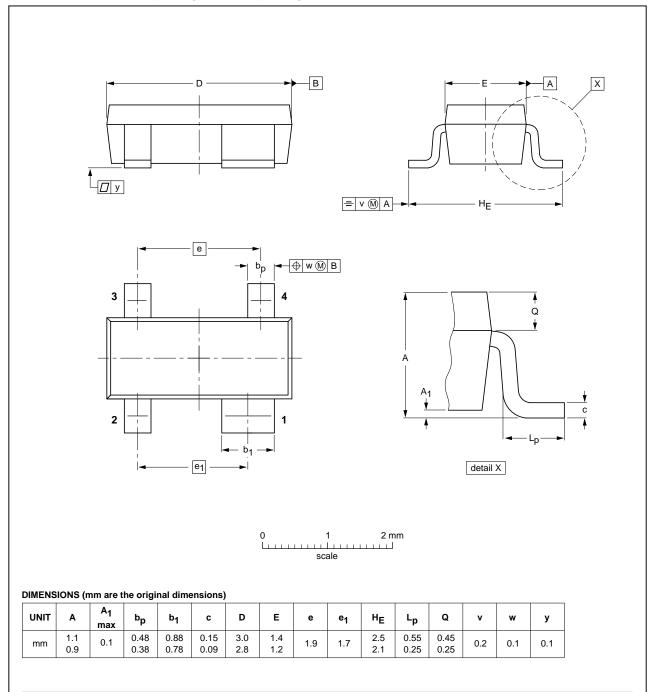
OUTLINE		REFER	ENCES	EUROPEAN	ISSUE DATE		
VERSION	IEC	JEDEC	JEITA		PROJECTION	ISSUE DATE	
SOT143B						04-11-16 06-03-16	

N-channel dual-gate PoLo MOS-FETs

BF1202; BF1202R; BF1202WR

Plastic surface-mounted package; reverse pinning; 4 leads

SOT143R



OUTLINE		REFERENCES						
VERSION	IEC	JEDEC	JEITA		PROJECTION	ISSUE DATE		
SOT143R			SC-61AA			-04-11-16- 06-03-16		

N-channel dual-gate PoLo MOS-FETs

BF1202; BF1202R; BF1202WR

Plastic surface-mounted package; reverse pinning; 4 leads

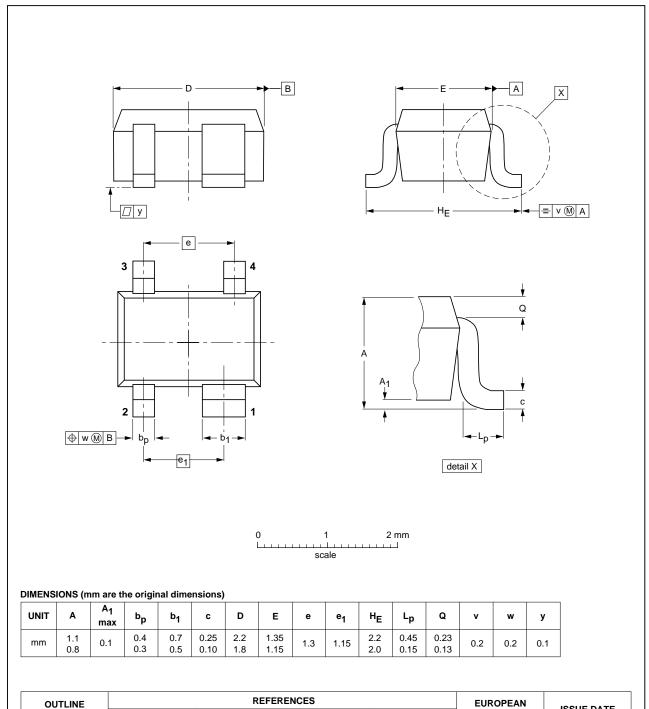
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PROJECTION



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VERSION

SOT343R

N-channel dual-gate PoLo MOS-FETs

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DATA SHEET STATUS

DOCUMENT STATUS ⁽¹⁾	PRODUCT STATUS ⁽²⁾	DEFINITION
Objective data sheet	Development	This document contains data from the objective specification for product development.
Preliminary data sheet	Qualification	This document contains data from the preliminary specification.
Product data sheet	Production	This document contains the product specification.

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